

# GEM TPC Resolution

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# TPC Setup

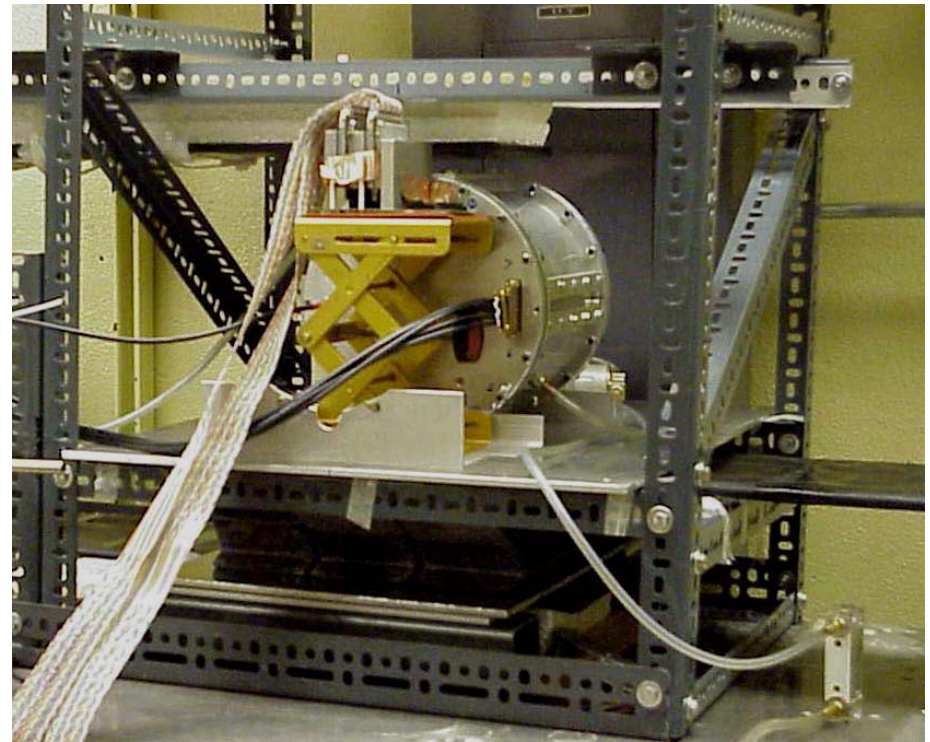
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15 cm drift distance  
cosmic ray particles  
gas: Ar:CO<sub>2</sub> (90:10); P10

ALEPH preamplifier  
custom FADC, 200 MHz  
University of Montreal

track resolution  
as function of

- position within pad
- pad width
- drift distance
- track angle
- amplitude



# Pad Layout

pad layout:

174 pads

+ trigger + veto

multiplexed  $\Rightarrow$  64 channels

outer rows (1,2,4,7,9,10):

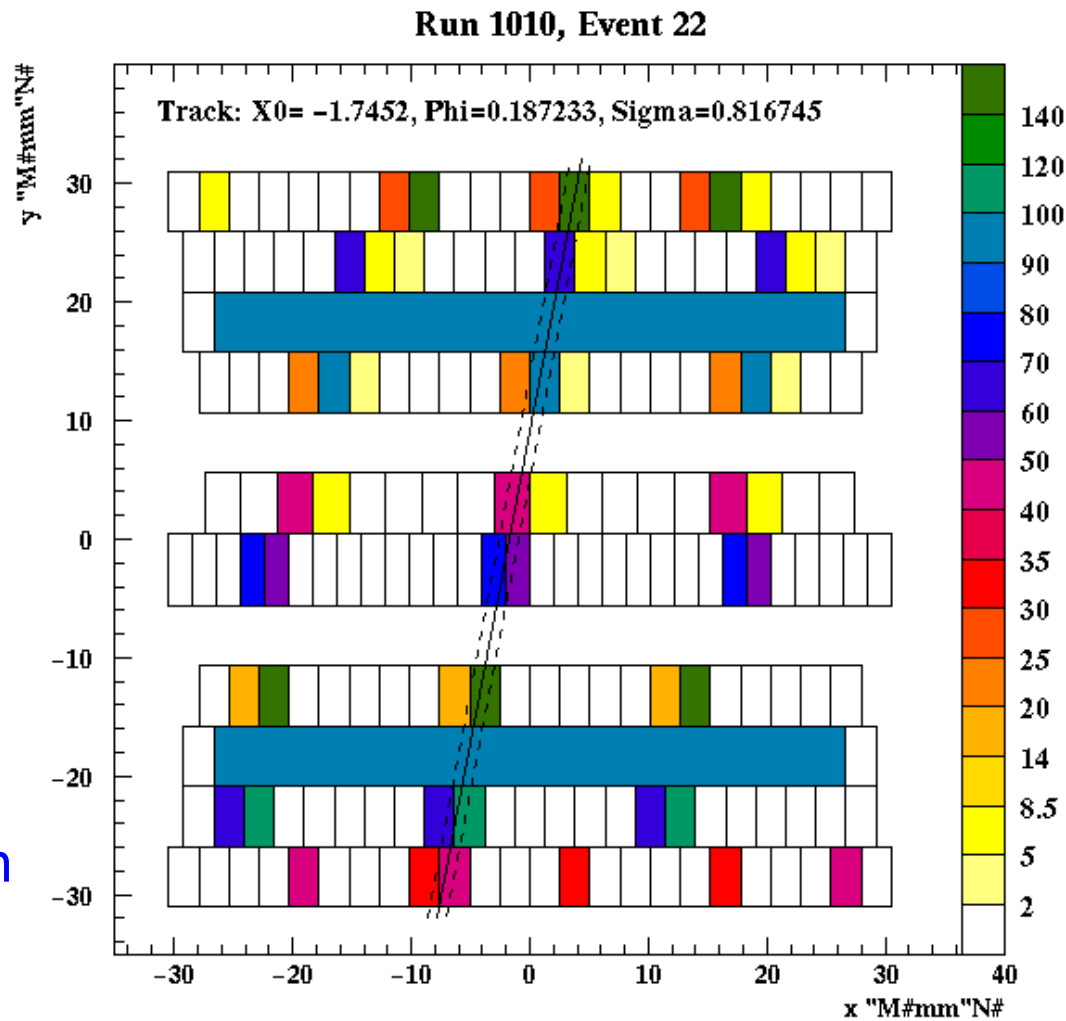
2.5 x 5 mm

row 5: 2 x 6 mm

row 6: 3 x 5 mm

all 8 rows used for track fit

1 row dropped for resolution



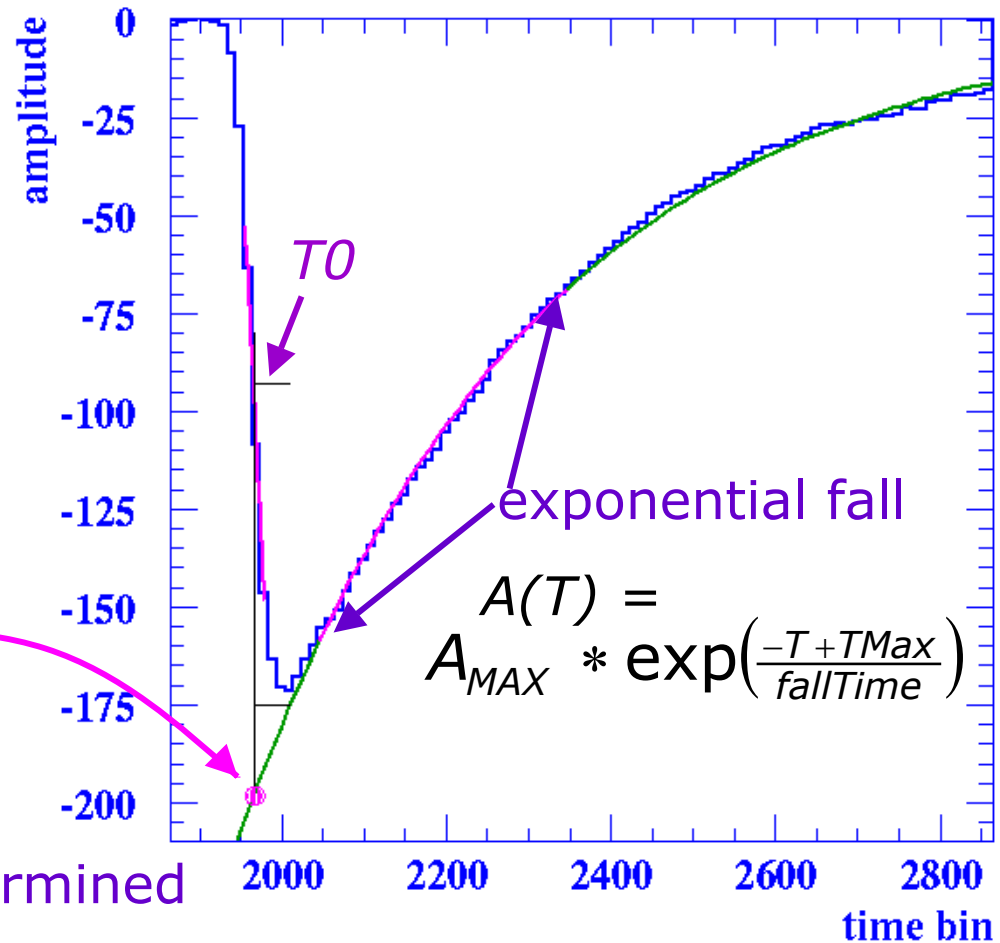
# Pulse Reconstruction

How to get amplitude and  $T_0$  from the ADC spectrum

- 1) Determine  $T_{Max}$   
time of max ADC value
- 2) 'fit' exponential in range  
 $[T_{Max}+50, T_{Max}+350]$   
using *fallTime(Group)*
- 3) Determine  $T_0$  as  
 $ADC(T_0) = A_{MAX}/2$   
from line to rising edge
- 4) Amplitude =  $A(T_0)$

fast to calculate and  
close to full fit

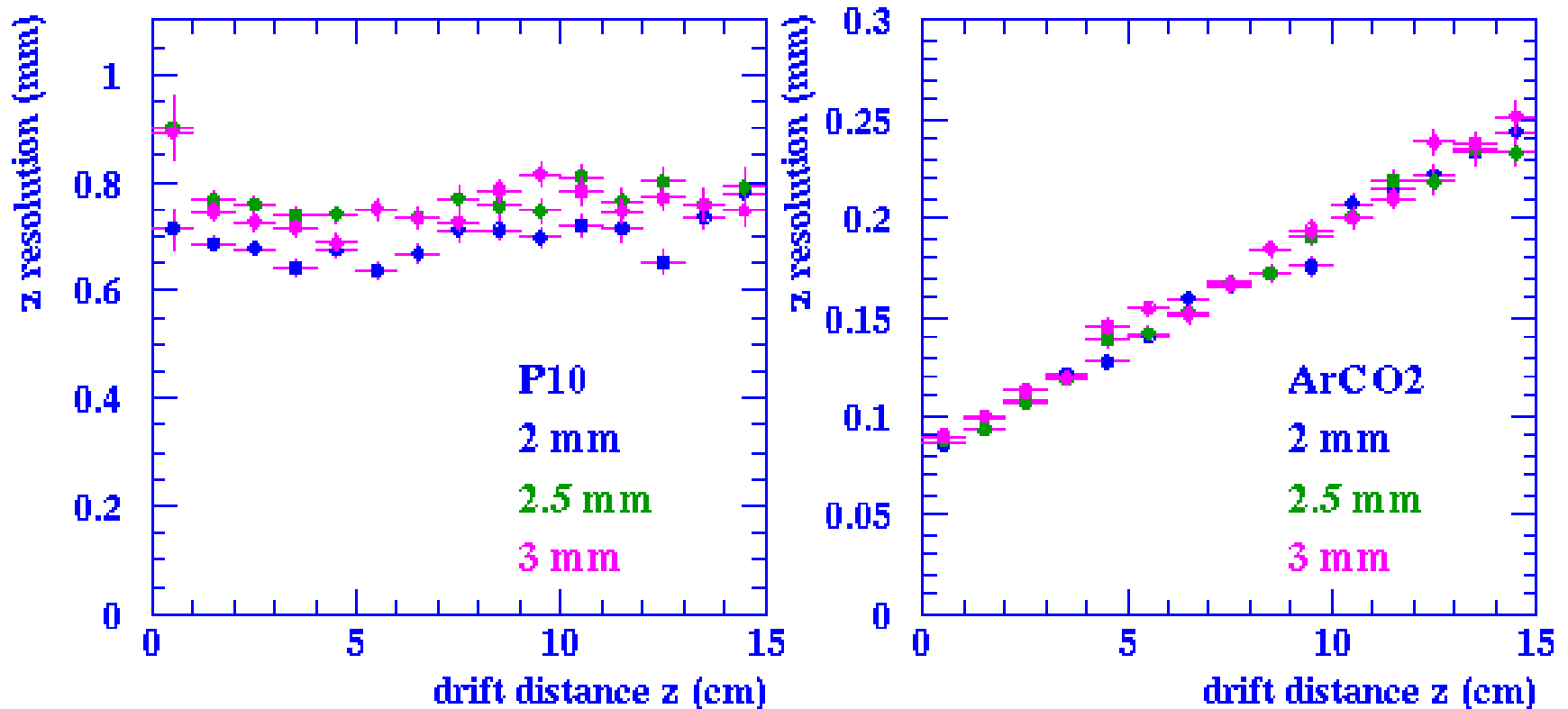
pedestal and *fallTime* are determined  
in calibration runs



# Z Resolution

Intrinsic time resolution  
~13ns for P10  
~9ns for ArCO<sub>2</sub>

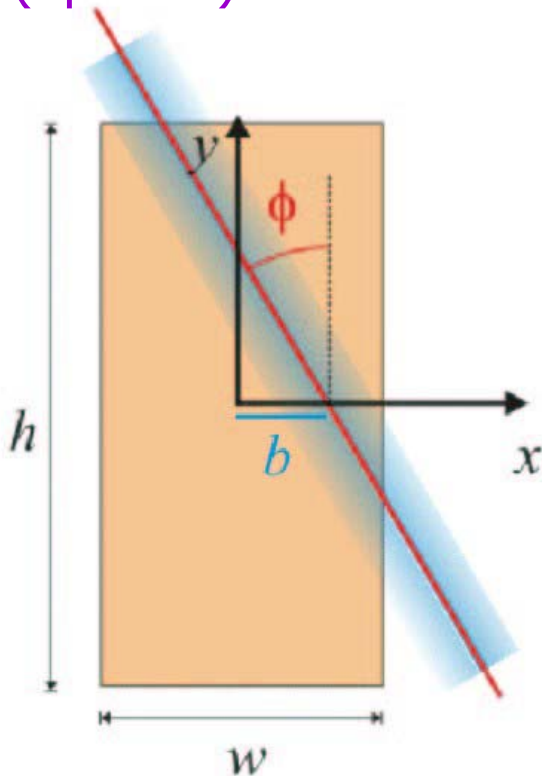
ArCO<sub>2</sub> very slow  
longitudinal diffusion visible  
effect is linear with drift distance !?!



# Track Fit

Dean Karlens method

3 track parameter:  
 $x_0$  (offset),  $\phi$  (angle)  
 $\sigma$  (spread)



assume uniform line of charge  
with Gaussian spread  $\sigma$

integral over pad  $\Rightarrow$  expected charge

normalized expectation across row  
gives probability

Likelihood =  $\Pi$  probability \* Amplitude

Resolution  $s$ :

fit only  $x_0$  to one row, compare to track  
row included in track fit  $\Rightarrow s_{in}$  too small  
row excluded in track fit  $\Rightarrow s_{ex}$  too large

Proper estimate of resolution:

$$s^2 = s_{in} * s_{ex}$$

# Naïve Theory

Charge width  $\sigma_{\text{track}}$ :

$$\sigma_{\text{track}}^2 = \sigma_0^2 + C_D^2 \cdot z$$

$$\sigma_0^2 = \sigma_{\text{hex}}^2 + \sigma_{\text{intern}}^2 + \sigma_{\text{other}}^2$$

hex: 37  $\mu\text{m}$

intern:  $\sim 300 \mu\text{m}$

Charge width  $\sigma_x$  across a row:

$$\sigma_x^2 = \sigma_0^2 + \sigma_D^2 + \sigma_\phi^2$$

$$\sigma_D = C_D \sqrt{z} / \cos \phi$$

$$\sigma_\phi = L / \sqrt{12} \tan \phi$$

X resolution  $s_x$ :

$$s_x^2 = s_0^2 + s_D^2 + s_\phi^2$$

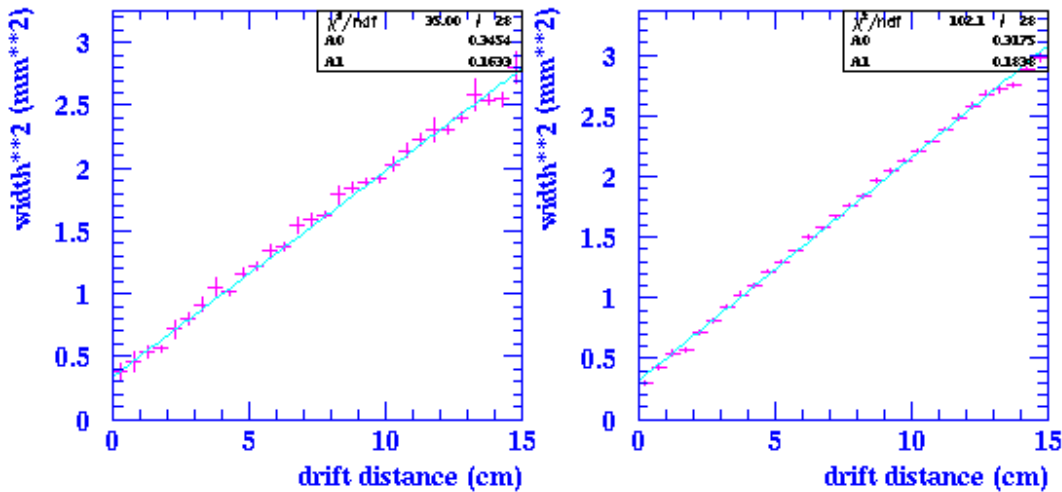
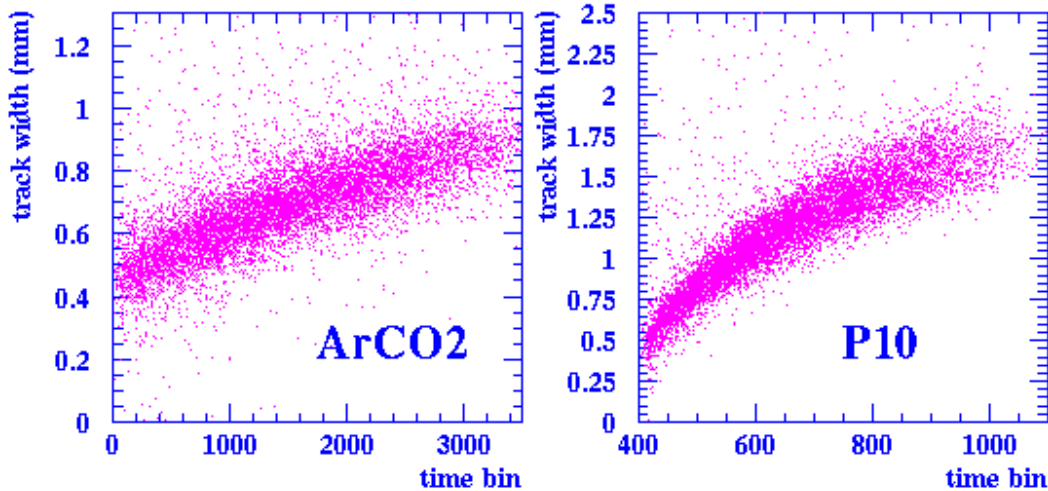
$$s_0 = \frac{\sigma_{\text{hex}}}{N_h} + \frac{\sigma_{\text{intern}}^2}{G_1 G_2 T N_t} + s_{\text{other}}^2$$

transverse diffusion:  $s_D = \sigma_D / \sqrt{R \cdot N_t}$

track angle effect:  $s_\phi = \sigma_\phi / \sqrt{N_{cl}^\epsilon}$

$N_t$  number of electrons  
 $N_{cl}$  number of clusters  
 $R$  Ratio  
 $\epsilon$  exponent [Blum]

# Track Width



determine  
transverse diffusion  $C_D$   
from track width

$$\sigma_{track}^2 = \sigma_0^2 + C_D^2 \cdot z$$

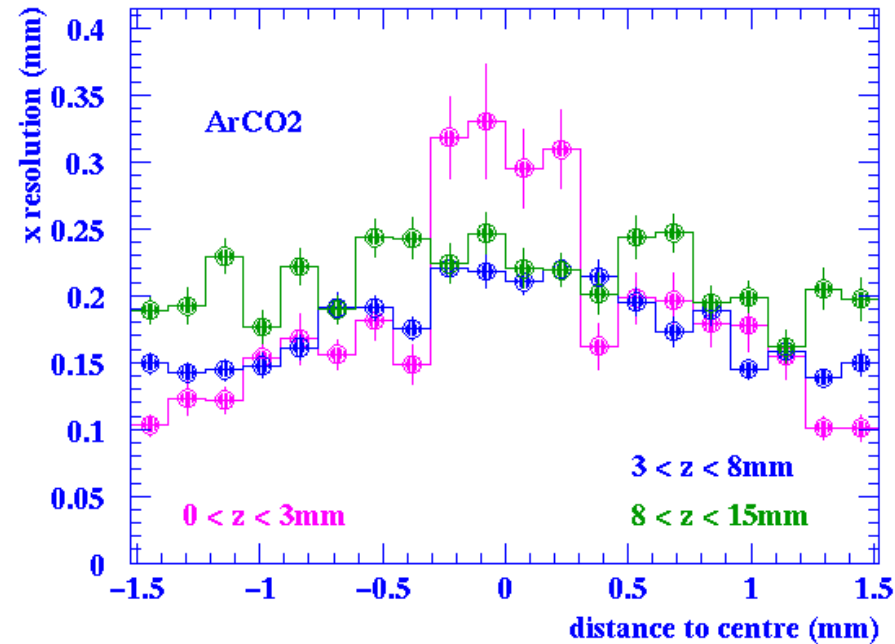
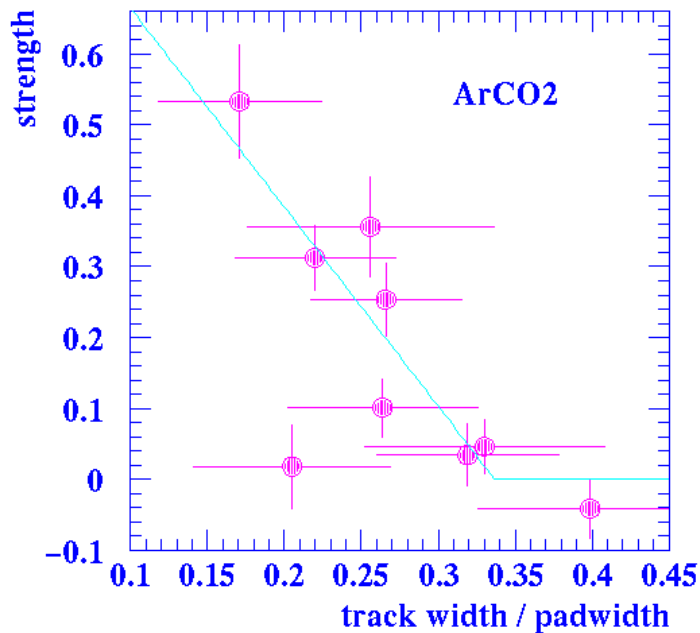
	$\sigma_0$ (mm)	$C_D$ $\left(\frac{mm}{\sqrt{cm}}\right)$
P10 (expected)	0.56 0.33	0.43 0.39
ArCO <sub>2</sub> (expected)	0.54 0.23	0.21 0.16



# Pad Width

3mm wide pads  
3 ranges of drift distance  
(= different charge width)

bad resolution at center of pad  
for small drift / small diffusion



Fraction of rows with one hit? Can be OK!  
information: no charge at neighbor pads

Hits not uniform distributed! Not OK!  
more hits in center of pad  
quantify as fraction

Not very accurate, depends on amplitude, ...

# Drift Distance

X resolution for small  $|\phi| < 5^\circ$

$$s_x^2 = s^2 + C_D^2 / (R \cdot N_t) z$$

average number of electrons

$N_t = 57$  (ArCO<sub>2</sub>), 55 (P10)

$C_D$  from our data

Fit full sample:

$R N_t = 19 \pm 7$  (ArCO<sub>2</sub>)

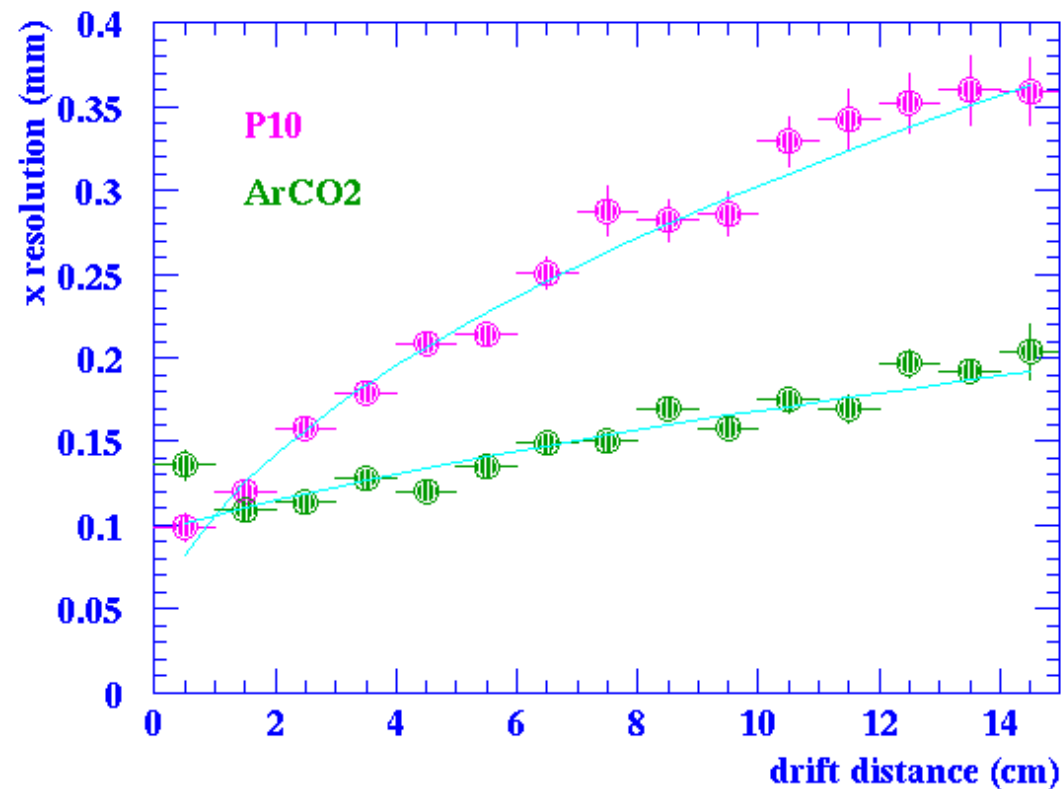
$20.6 \pm 0.7$  (P10)

Wide range of amplitudes:

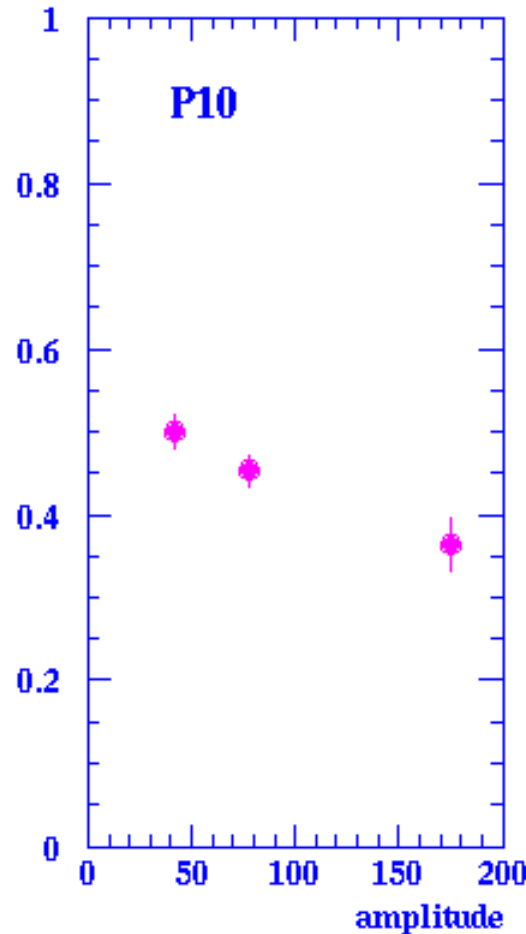
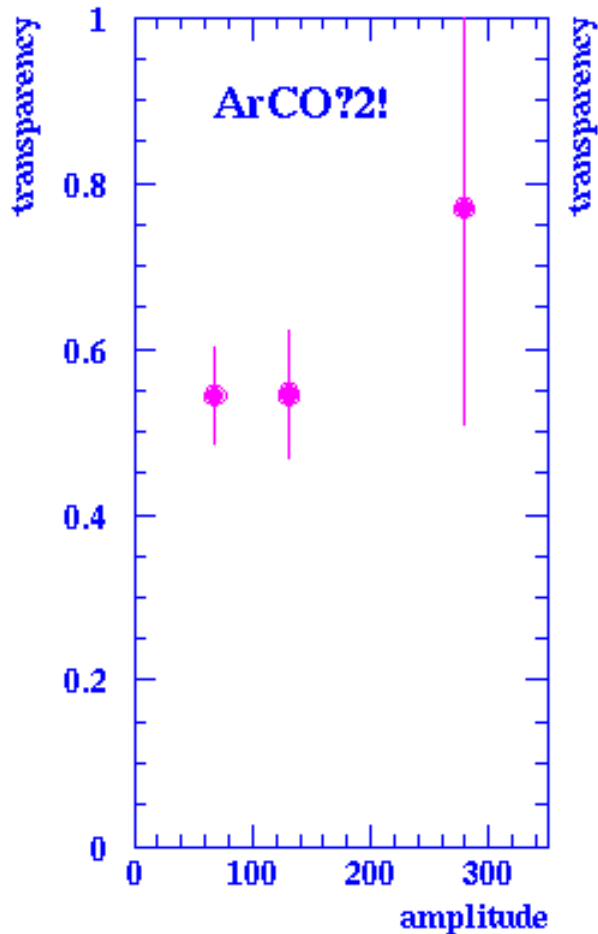
$$\langle A \rangle \approx 1.3 / \left( \langle 1/\sqrt{A} \rangle \right)^2$$

mean  $N_t$  in fit is smaller  
by 30% from naïve guess

⇒ split sample



# Statistics



3 regions of amplitude  
2 gasses

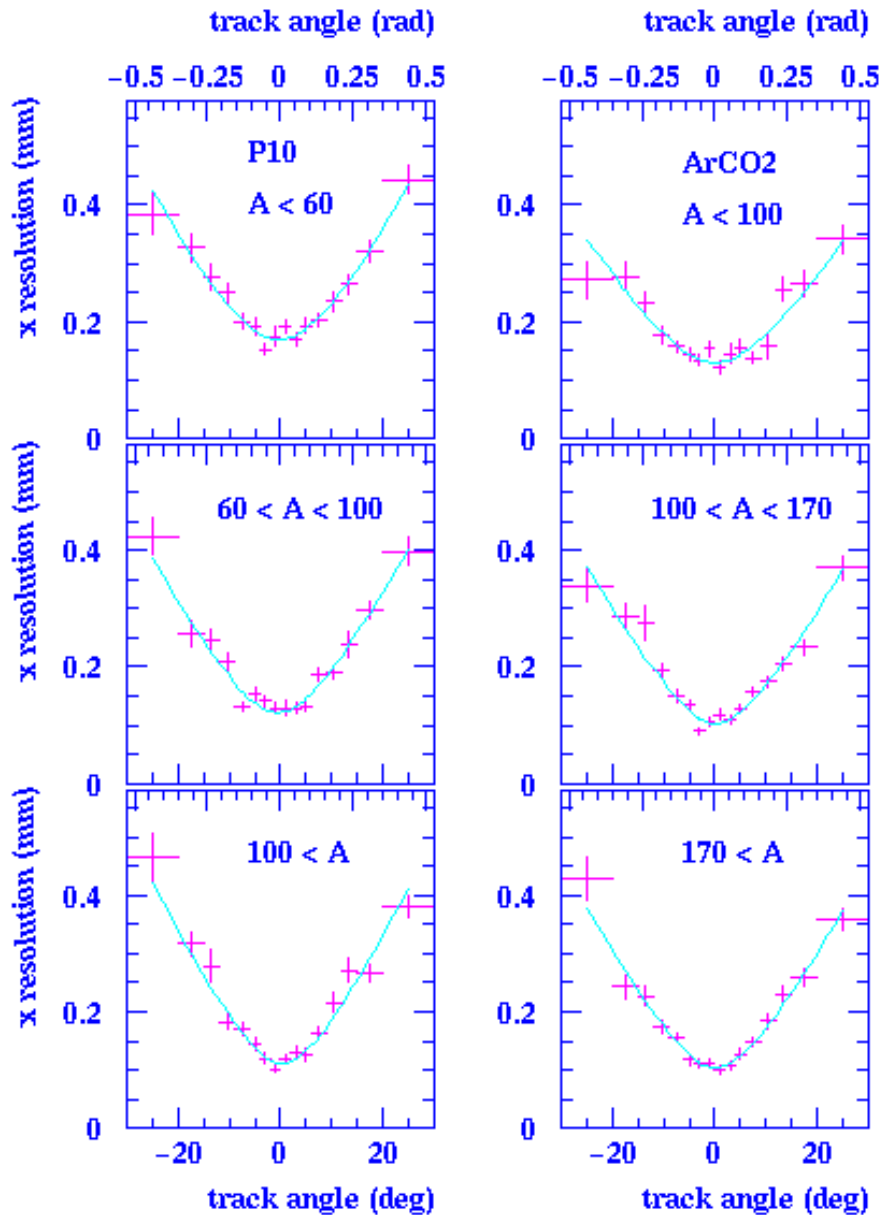
$N_t$  too small by 10%

from fits we obtain  
ratio  $R \cong 50\%$   
in naïve model

we make use of only  
half the statistical power

for one reason  
or another

# Track Angle



small drift:  $z < 3$  cm

$$s_x^2 = s^2 + \frac{L^2}{12 \cdot N_{cl}^\varepsilon} \tan^2(\phi - \varphi)$$

$\varphi$ : systematic offset in  $\phi$   
consistent with 0

$\varepsilon$ : reduction of number of clusters  
 $\cong 0.5$  no significant dependence

$s$ : decreases with amplitude  
dominated by transverse diffusion

simple model describes  
the data well

no surprises

# Conclusion

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Comprehensive study of track resolution with GEM TPC  
No magnetic field, gasses: Ar:CO<sub>2</sub> (90:10) and P10

- for good resolution: charge width > pad width /3
- charge width at small drift much wider than expected  
~ 500 μm unexplained
- track angle effect  
no systematic bias in  $\phi$   
weak dependence on number of clusters:  $s_\phi \sim 1/\sqrt[4]{N_{cl}}$   
base resolution improves with amplitude
- x resolution as function of drift distance  
for 3 regions of amplitude and both gasses  
make use of only about half the statistical power

Need to understand why resolution at large drift distance  
doesn't improve with statistics as expected.